

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Yutaka YONEDA et al.

International Application No.: PCT/JP03/15894

International Filing Date: December 11, 2003

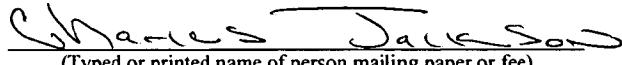
For: PIXEL DEFECT DETECTING AND CORRECTING APPARATUS AS WELL AS PIXEL DEFECT DETECTING AND CORRECTING METHOD

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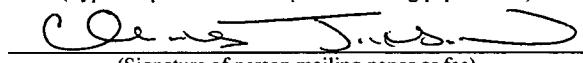
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INFORMATION DISCLOSURE STATEMENT

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Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/15894. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

In the event the above-identified patent application was filed after June 30, 2003 or is an international application that entered the national stage under 35 U.S.C. 371 after June

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PATENT

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30, 2003, no copy of any cited U.S. patent or U.S. patent application publication is provided.

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In the event the above-identified patent application was filed under 35 U.S.C. 111 on or after June 30, 2003, or is an international application that entered the national stage on or after June 30, 2003, no copy of the specification, claims or drawings of any cited pending U.S. patent application is provided. See, "Waiver of the Copy Requirement in 37 CFR 1.98 for Cited Pending U.S. Patent Applications" as stated in the Notice published in the Official Gazette of October 19, 2004.

#### REMARKS

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP  
Attorneys for Applicants

By:



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Enclosures

Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 450100-04854	EXAMINER 10/05/2005 Filed Concurrently Herewith
	APPLICANT Yutaka YONEDA et al.	
	FILING DATE Filed Concurrently Herewith	GROUP

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	JP 2002-271806	09/20/02	Japan			
	AM	JP 10-243300	09/11/98	Japan			
	AN	JP 2001-54127	02/23/01	Japan			
	AO	JP 2003-158744	05/30/03	Japan			
	AP						

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ						
	AR						
	AS						

EXAMINER  /Timothy Henn/	DATE CONSIDERED  10/01/2008
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